Atmos. Meas. Tech. Discuss., 5, C4012–C4013, 2013
www.atmos-meas-tech-discuss.net/5/C4012/2013/

Atmospheric
Measurement
Techniques
Discussions

Interactive comment on “Biases caused by the instrument bandwidth and beam width on simulated brightness temperature measurements from scanning microwave radiometers” *by* V. Meunier et al.

V. Meunier et al.

veronique.meunier2@mail.mcgill.ca

Received and published: 25 February 2013

Dear Reviewer,

The response to your comments and concerns is found in the attached PDF file.

Cheers, Veronique Meunier

Please also note the supplement to this comment:
http://www.atmos-meas-tech-discuss.net/5/C4012/2013/amtd-5-C4012-2013-supplement.pdf

---

Interactive comment on Atmos. Meas. Tech. Discuss., 5, 8085, 2012.